

Notice of Referenc s Cited

Application/Control No. 08/807,737	וקקי licant(s)/Patent Under Reexamination OHTANI ET AL		
Examiner	Art Unit		
Evan T. Pert	2813	Page 1 of 1	
Evan T. Pert	2813	Page 1 of 1	

-								Page 1 of 1		
*	T	DOO! IN CASE AND			NT DOCUMENTS		7	DOCUM	MENT	
L	\perp	DOCUMENT NO.	DATE		NAME		SUBCLASS	SOURCE	E **	
) A	5,403,772	Apr. 1995	Zhang et al.				APS ⊠	OTHER	
) B	5,311,041	May. 1994	Tominaga et a	al.				 	
) c	5,273,920	Dec. 1993	Kwasnick et al	l.			⊠		
] D	4,915,772	Apr. 1990	Fehlner et al.				⊠		
15) E	4,330,363	May. 1993	Biegesen et a	ıl.			⊠		
	F									
	G		3							
	Н									
ㅁ	<u> </u>									
	J				·					
	к									
	L									
□	М									
*	$\overline{}$			FOREIGN PAT	TENT DOCUMENTS	1		T BOOLING	<u> </u>	
		DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUBCLASS	SOURCE	DOCUMENT SOURCE **	
	N							APS	OTHER	
	0									
		,								
	Р									
	Q									
	R									
	S									
	Т									
\neg	\neg			NON-PATEN	T DOCUMENTS			T DOCUMEN	U2	
*		DOCUMENT (Including Author, Title Date, Source, and Pertinent Pages)						DOCUMENT SOURCE **		
7								APS	OTHER	
	U	B.C. Ahn et al., "Batch-Processing of High-Performance Amorphous-Silicon/Silicon Nitride Thin-Film Transistors", Oct. 1991, IEEE Display Research Conference, pages 85-88.								
	V	Sera et al., "High-Performan Amorphous-Silicon Film", 19	enated es 2868-2872.							
	w	W Zhang et al., "KrF Excimer Laser Annealed TFT with Very High Field-Effect Mobility of 329 cm2/Vs", 1992, IEEE Electron Device Letters, Vol. 13, No. 5, pages 297-299								
	x	_		-						

*A copy of this reference is not being furnished with this Office action. (See Manual of Patent Examining Procedure, Section 707.05(a).)

**APS encompasses any electronic search i.e. text, image, and Commercial Databases.

U.S. Patent and Trademark Office
PTO-892 (Rev. 03-98)

Notice of References Cited